

Subject Coverage

- Atomic and molecular physics
- Circuit theory and circuits
- Classical areas of phenomenology
- Communications
- Components, electronic devices and materials
- Computer applications
- Computer hard- and software
- Condensed matter: structure, mechanical properties, electronic structures, electrical, magnetic, and optical properties
- Control technology
- Cross-disciplinary physics and related areas of science and technology
- Electromagnetic fields
- Engineering mathematics, materials science
- Fluids, plasmas, electric discharges
- General and management aspects and applications
- Geophysics, astronomy, astrophysics
- Information technology
- Instrumentation and special applications
- Magnetic and superconducting materials and devices
- Mechanical engineering
- Nuclear physics
- Numerical analysis and theoretical computer topics
- Office automation - communications, computing
- Optical materials and applications, electro-optics and optoelectronics
- Physics of elementary particles and fields
- Power systems and applications
- System and control theory

File Type

Bibliographic

Features

| | | | |
|-----------------------------------|---|-----------------------|-------------------------------------|
| Thesaurus | Controlled Term (/CT), International Patent Classification (/IPC), Physical Properties (/PHP) | | |
| Alerts (SDIs) | Weekly | | |
| CAS Registry Number® Identifiers | <input type="checkbox"/> | Page Images | <input type="checkbox"/> |
| Keep & Share | <input checked="" type="checkbox"/> | SLART | <input checked="" type="checkbox"/> |
| Learning Database | <input checked="" type="checkbox"/> | Structures | <input type="checkbox"/> |

Record Content

- Bibliographic information, indexing terms, abstracts and International Patent Classification, where applicable.
- INSPEC also includes an archive from 1898-1968. This archive provides access to Science Abstracts Journals from 1898-1968, and contains over 873,700 records with the original value-added indexing and classifications, as well as enhancements in the form of the nearest equivalent current INSPEC Thesaurus terms and INSPEC Classification Codes.
- IPC codes are available from 2010 onwards.
- There are more than 2.6 Million citations mostly from 2010 onwards, with about 300 Thousand added each year.

File Size

More than 21.2 million citations (04/2021)

| | |
|--------------------------|---|
| Coverage | 1898-present |
| Updates | Weekly |
| Language | English |
| Database Producer | <p>The Institution of Engineering and Technology (IET) Michael Faraday House, Six Hills Way Stevenage, Herts SG1 2AY, United Kingdom Phone: +44 1438/313311 Fax: +44 1438/742840 Email: inspec@theiet.org</p> <p>Copyright Holder</p> <p>The Institution of Engineering and Technology is registered as a Charity in England & Wales (no 211014) and Scotland (no SC038698)."</p> |
| Database Supplier | <p>FIZ Karlsruhe P.O. Box 2465 76012 Karlsruhe Germany Phone: +49 7247 808-555 Fax: +49 7247 808-259 Email: helpdesk@fiz-karlsruhe.de</p> |
| Sources | <ul style="list-style-type: none">• Journals• Reports• Conferences• Books• Dissertations• Patents (until 1976) |
| User Aids | <ul style="list-style-type: none">• Inspec List of Journals *• Inspec Classification *• Inspec Thesaurus *• IPC Codes Applied in Inspec Records https://www.theiet.org/media/7694/ipc-patent-codes.pdf• Online Helps (HELP DIRECTORY lists all help messages available)• STNGUIDE <p>* available printed at producer and online</p> |

Clusters

- AEROTECH
- ALLBIB
- AUTHORS
- CHEMENG
- CHEMISTRY
- COMPUTER
- CORPSOURCE
- ELECTRICAL
- ENGINEERING
- ENVIRONMENT
- FUELS
- GEOSCIENCE
- GOVREGS
- MATDATA
- MATERIALS
- MEETINGS
- METALS
- METDATA
- PETROLEUM
- NPS
- PHYSICS
- SAFETY

STN Database Cluster information:

<http://www.stn-international.com/en/customersupport/customer-support#cluster+%7C+subjects+%7C+features>

**Related
Databases**

INSPHYS

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

| Search Field Name | Search Code | Search Examples | Display Codes |
|---|-------------------|--|------------------------|
| Basic Index* (contains single words from abstract (AB), controlled term (CT), supplementary term (ST), controlled term original (CTO), and title (TI) fields) | None or /BI | S MICROELECTRON? S QUANTUM HALL S LIQUID(A)CRYST? S AL203-NA20 S ?LASER? | AB, CT, CTO, ST, TI |
| Abstract* | /AB | S NEUTRON ?RADIATION?/AB | AB |
| Accession Number | /AN | S 1990:3615482/AN | AN |
| Application Date (1) | /AD | S AD = APR 1969 | AI |
| Application Year (1) | /AY | S AY = 1970 | AI |
| Astronomical Object | /AO | S WESTERBORK-19 32/AO S 1101+38/AO | AO |
| Author | /AU | S SMITH S/AU S SMITH, S/AU | AU |
| Availability (2) | /AV | S NASA CENTER/AV | AV |
| Chemical Indexing | /CHI (or /MAI) | S BA DOP/CHI S CU SS/CHI S SS304 BIN/CHI | CHI |
| Classification Code (contains INSPEC classification) | /CC | S A9110Q/CC S A4/CC S A41/CC | CC |
| Classification Code, Original (2) | /CCO | S OPTICAL DEVICE?/CC S MATHEMATICAL PHYSICS/CCO S 621.791/CCO | CCO |
| Controlled Term (4) | /CT | S MAGNETIC LEVITATION/CT | CT |
| Controlled Term, Original (2) | /CTO | S "MANGANESE BISMUTHIDE"/CTO | CTO |
| Controlled Word | /CW | S MAGNETIC/CW | CT, CTO |
| Corporate Source (incl. affiliation, patent assignee) | /CS | S (NAT(W)BUR?(2W)WASH?)/CS S GAIN ELECTRON?/CS | CS |
| Corporate Source Identifier (Ringgold Identifier (RIN)) | /CSID | S 120034/CSID | CSID |
| Digital Object Identifier | /FTDOI | S HTTPS://DOI.ORG/10.0002/ER.802/FTDOI | FTDOI |
| Document Number | /DN | S C1983-014353/DN | DN |
| Document Type (code and text) | /DT (or /TC) | S Book/DT S GENERAL REVIEW/DT | DT |
| E-mail Address (3) | /EML | S HEIDEL IBM/EML | AU, EML |
| Entry Date (1) | /ED | S ED>JAN 2006 | ED |
| File Segment | /FS | S B/FS AND SAFETY | FS |
| International Patent Classification (2,7) | /IPC | S B82B0001-00/IPC | IPC |
| International Standard (Document) Number (contains ISSN, ISBN, and CODEN) (2) | /ISN | S 1220-3033/ISN S 1-88044-651-0/ISN S AABNAC/ISN | SO, ISN |

General Search Fields (cont'd)

| Search Field Name | Search Code | Search Examples | Display Codes |
|--|----------------------|--|------------------|
| Journal Title (contains full and abbreviated titles) | /JT | S CREATIVE COMPUT?/JT | JT, JTA, JTF, SO |
| Language (ISO code and text) | /LA | S GERMAN/LA S RU/LA | LA |
| Meeting Date (1) | /MD | S 15 DEC 1999/MD | MD, SO |
| Meeting Location (3) | /ML | S NANTES/ML | ML, SO |
| Reference Count (1) | /REC (or /RE.CNT) | S L1 AND REC<10 | REC, SO |
| Meeting Year (1) | /MY | S 1983-1984/MY | MY, SO |
| Note (2) | /NTE | S ALSO PUBLISHED/NTE | NTE |
| Number of Contract | /NC | S 016-77-1 RPU B/NC | NC |
| Number of Report (number and prefix) | /NR | S GEPP-8/NR S GEPP/NR | NR |
| Patent Assignee (3, 5) | /PA | S BATTELLE CORP/CS | PA |
| Patent Country (WIPO code and text) (5) | /PC | S GB/PC | PNO |
| Patent Number, Original (5) | /PNO (or /PATS) | S GB1 122 151/PNO | PNO |
| Priority Date (1,5) | /PRD | S DEC 1960/PRD | PRAO |
| Priority Number, Original (5) | /PRNO | S AUSTRALIA006404/PRNO | PRAO |
| Priority Year (1,5) | /PRY | S PRY>1965 | |
| Publication Date (1) | /PD | S JAN 2004-MAR 2004/PD | PD, SO |
| Publication Year (1) | /PY | S 2004-2005/PY | SO, PNO |
| Publisher (3) | /PB | S MCGRAW LONDON/PB | PB, SO |
| Reference (2) | /RE | S LANDRY M/RE | RE |
| Source (contains CODEN, journal title and other higher level titles, ISBN, ISSN, SICI, Internet URL, publisher, meeting information, number of contract, number of report) | /SO | S EARTH PLANET/SO S (CREATIVE COMP?(L)USA)/SO S 0031-9201/SO S WWW.COMPUTER.ORG/SO S AABNAC/SO | SO |
| Supplementary Term | /ST | S AL2O3-NA2O/ST S MEASUR? DEVICE#/ST | ST |
| Title* | /TI | S GRAVITY PARAMETERS/TI | TI |
| Uniform Resource Locator (3) | /URL | S JHEP ARCHIVE/URL | URL, SO |
| Update Date (1) | /UP | S UP=FEB 2009 | UP |
| Word Count, Title (1) | /WC.T | S L1 AND WC.T>10 | WC.T |

- (1)** Numeric search field that may be searched using numeric operators or ranges.
(2) Field available for data since 1969 only.
(3) Search with implied (S) proximity is available in this field.
(4) An online thesaurus is available in this field.
(5) Field available until 1976.

Property Fields¹⁾

In INSPEC a numeric search for a specific set of physical properties (/PHP) is available within the text fields (TI, AB, BI). The numeric values are not displayed as single fields, but highlighted within the hit displays.

Use EXPAND/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

| Field Code | Property | Unit | Symbol | Search Examples |
|--------------|---------------------------------|------------------------|-------------------|---|
| /AOS | Amount of substance | Mol | mol | S 10 /AOS |
| /BIR | Bit Rate | Bit/Second | bit/s | S 8000-10000/BIR |
| /BIT | Stored Information | Bit | Bit | S BIT > 3 MEGABIT |
| /CAP | Capacitance | Farad | F | S 1-10 MF/CAP |
| /CATA | Catalytic Activity | Katal | kat | |
| /CDN | Current Density | Ampere/Square Meter | A/m ² | S CDN>10 A/M**2 |
| /CMOL | Molarity, Molar Concentration | Mol/Liter | mol/L | S UREA/BI (S) 8/CMOL |
| /CON | Conductance | Siemens | S | S 1S-3/CON |
| /DB | Decibel | Decibel | dB | S DB>50 |
| /DEG | Degree | Degree | ° | S CYLINDER/BI (S) 45/DEG |
| /DEN (/C) | Density (Mass Concentration) | Kilogram/Cubic Meter | kg/m ³ | S 5E-3-10E-3/DEN |
| /DEQ | Dose Equivalent | Sievert | Sv | S 100/DEQ |
| /DOA | Dosage | Milligram/Kilogram/Day | mg/day | |
| /DOS (/LD50) | Dose | Milligram/Kilogram | mg/kg | S DOS>0.8 |
| /DV | Viscosity, dynamic | Pascal * Second | Pa * s | S DV>5000 |
| /ECH (/CHA) | Electric Charge | Coulomb | C | S 0.0001-0.001/ECH |
| /ECO (/ECND) | Electrical Conductivity | Siemens/Meter | S/m | S ECO>800 S/M (15A) AQUEOUS |
| /ELC (/ECC) | Electric Current | Ampere | A | S 1-10/ELC |
| /ELF (/ECF) | Electric Field | Volt/Meter | V/m | S 200/ELF |
| /ENE | Energy | Joule | J | S DROPLETS (10A) 40 JOULE - 70 JOULE /ENE S ERE>0.1 |
| /ERE (/ERES) | Electrical Resistivity | Ohm * Meter | Ohm * m | |
| /FOR | Force | Newton | N | S 50 N /FOR |
| /FRE (/F) | Frequency | Hertz | Hz | S OSCILLAT?/BI (S) 1- 3/FRE |
| /IU | International Unit | none | IU | S IU>1000 (P) VITAMIN A |
| /KV | Viscosity, kinematic | Square Meter/Second | m ² /s | S METHYLPOLYSILOXANES/BI (10A) 200-300 CST /KV S 1-4/LEN |
| /LEN (/SIZ) | Length, Size | Meter | m | |
| /LUME | Luminous Emittance, Illuminance | Lux | lx | S 10-50/LUME |
| /LUMF | Luminous Flux | Lumen | Lm | S LUMF>1000 |
| /LUMI | Luminous Intensity | Candela | cd | S LUMI<4 |
| /M | Mass | Kilogram | kg | S ALLOY/BI (30A) 1E-10-1E-5/M |
| /MCH | Mass to Charge Ratio | none | m/z | S MCH=1 |
| /MFD (/MFS) | Magnetic Flux Density | Tesla | T | S MFD>102 |
| /MFR (/MFL) | Mass Flow Rate | Kilogram/Second | kg/s | S MFR<0.1 |
| /MFST | Magnetic Field Strength | Ampere/Meter | A/m | |

Property Fields₁₎ (cont'd)

| Field Code | Property | Unit | Symbol | Search Examples |
|-----------------|--|-----------------------|--------------------|---|
| /MM (/MW, /MOM) | Molar Mass | Gram/Mol | g/mol | S 2000-3000 G/MOL/MM |
| /MOLS /MVR | Molality of Substance Melt Volume Rate, Melt Flow Rate | Mol/Kilogram none | mol/kg g/10 min | S 01.-10 MOL/KG/MOLS S 3/MVR |
| /PER | Percent (Proportionality) | none | % | S POLYMER?/AB (5A) 4/PER |
| /PHV (/PH) | pH Value | pH | pH | S 7.4-7.6/PHV |
| /POW (/PW) | Power | Watt | W | S "HG-XE-?"/BI (S) 100-200 WATT/POW |
| /PPM | Parts per million | Ppm | ppm | S 100 PPM /PPM (10A) ADDITIVE/BI |
| /PRES (/P) | Pressure | Pascal | Pa | S (VACUUM (5A) DISTILL?)/BI (S) 1000-1100/PRES |
| /RAD | Radioactivity | Becquerel | Bq | S RAD/PHP |
| /RES | Electrical Resistance | Ohm | Ohm | S SENSOR /BI (S) 10- 100/RES |
| /RI | Refractive Index | none | | S 3-4/RI |
| /RSP | Rotational Speed | Revolution/Minute | rpm | S 2 RPM - 100 RPM /RSP (S) ENGINE/BI |
| /SAR | Area /Surface Area | Square Meter | m ² | S PLATE/BI (S) 10 M**2 - 100 M**2 /SAR |
| /SOL (/SLB) | Solubility | Gram/100 gram | g/100 g | S SOL>20 G/100G (5A) WATER |
| /SSAM | Specific Surface Area, Mass | Square Meter/Kilogram | M2/kg | |
| /STSC (/ST) | Surface Tension | Joule /Square Meter | J/m ² | S 60 J/M**2/STSC |
| /TCO (/TCND) | Thermal Conductivity | Watt/Meter * Kelvin | W/m * K | S 1/TCO (S) HEAT? |
| /TEMP (/T) | Temperature | Kelvin | K | S 20-25/TEMP |
| /TEX | Tex | Gram/Kilometer | g/km | |
| /TIM | Time | Second | s | S ?INCUB?/BI (10A) 50 S - 150 S /TIM |
| /VEL (/V) | Velocity | Meter per Second | m/s | S REDUC?/BI (S) 1E-3-5E-3/VEL |
| /VELA | Velocity, angular | Radian/Second | rad/s | S VELA>10 |
| /VLR | Volumetric Flow Rate | Cubic Meter/Second | m ³ /s | S 1 M**3/S - 2 M**3/S /VLR (S) ABRASIVE |
| /VOL | Volume | Cubic Meter | m ³ | S 1E-8-2E-8/VOL.EX |
| /VOLT | Voltage | Volt | V | S TENSION/BI (10A) 5E-3 V <VOLT<7E-3 V |

(1) Exponential format is recommended for the search of particularly high or low values, e.g. 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

Controlled Term (/CT) Thesaurus

All Relationship Codes can be used with both the SEARCH and EXPAND command.

| Code | Content | Examples |
|------------------------------------|---|--|
| ALL AUTO (1) BT HIE KT | All Associated Terms Automatic Relationship (SELF, USE, UF) Broader Terms (also BT1, BT2 etc. possible) Hierarchy (all Broader and Narrower Terms) Keyword Terms (Multi-word Phrases containing the specified Keyword Term) | E ALUMINIUM COMPOUNDS+ALL/CT S POWDER SPRAYING+AUTO/CT E TERBIUM ALLOYS+BT/CT E SHOCK WAVES+HIE/CT E POWDER+KT/CT |
| NOTE NT PFT PT | Notes associated with Terms (SELF, DA, CC) Narrower Terms (also NT1, NT2 etc. possible) All Preferred, Forbidden Terms, and Dates (SELF, DA, USE, UF) Prior Terms | E ELECTRIC MACHINES+NOTE/CT S ACOUSTIC TRANSDUCERS+NT/CT E POWER AMPLIFIERS+PFT/CT E DATABASE MANAGEMENT SYSTEMS+PT/CT |
| RT STD | Related Terms (see also) Standard (all Broader, Narrower, Related, and Prior Terms) | E TRANSIENT ANALYSERS+RT/CT E TRANSFER FUNCTIONS+STD/CT |
| UF USE | Used For (Preferred and Forbidden Terms) Use (Forbidden and Preferred Terms) | E TRANSDUCERS+UF/CT E SOLIONS+USE/CT |

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

| Code | Content | Examples |
|--|---|---|
| ADVANCED (ADV) ALL BRO (MAN) BT CORE (COR) ED HIE INDEX KT NEXT NT PREV RT (SIB) TI | Advanced Codes for the Core Level IPC Code All Associated Terms (BT, SELF, NT, RT) Complete Class Broader Term (BT, SELF) Core Codes for the Advanced Level IPC Code Complete title of the SELF term and IPC manual edition Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT) Complete title of the SELF term Keyword Term (catchwords) (SELF, KT) Next Classification Narrower Terms (SELF, NT) Previous Classification Related Terms (SELF, RT) Complete Title of the SELF Term and Broader Terms (BT, SELF) | E A61K0006-02+ADVANCED/IPC E C01C003-00+ALL/IPC E C01C+BRO/IPC E C01F001-00+BT/IPC E G08C0019-22+CORE/IPC E C01F001-00+ED/IPC E C011003-00+HIE/IPC E C01F001-00+INDEX/IPC E CYANOGEN+KT/IPC E C01C001-00+NEXT5/IPC E C01C+NT/IPC E C01C001-12+PREV10/IPC E C01C003-20+RT/IPC E C01F001-00+TI/IPC |

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields except AU and CS. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

| Format | Content | Examples |
|------------------|---|----------|
| AB | Abstract | D TI AB |
| AI | Application Information | |
| AN | Accession Number | D 1-5 AN |
| AO | Astronomical Object | D AO |
| AU | Author | D AU TI |
| CC | Classification Code | D CC |
| CCO | Classification Code, Original | D CCO |
| CHI | Chemical Indexing | D CHI |
| CS | Corporate Source (format includes AU) | D CS |
| CSID (1) | Corporate Source Identifier (Ringgold Identifier (RIN)) | D CSID |
| CT | Controlled Term | D CT |
| CTO | Controlled Term, Original | D CTO |
| CY | Country | D CY |
| DN | Document Number | D AN DN |
| DT | Document Type (incl. Treatment Code) | D DT |
| ED | Entry Date | D ED |
| EML (1) | E-mail Address | D EML |
| ET | Element Terms | D ET |
| FS (1) | File Segment | D FA |
| FTDOI (1) | Digital Object Identifier | D FTDOI |
| IPC | International Patent Classification | D IPC |
| ISN (1) | International Standard (Document) Number | D ISN |
| JT (1) | Journal Title | D JT |
| JTA (1) | Journal Title, Abbreviated | D JTA |
| JTF (1) | Journal Title, Full | D JTF |
| LA | Language | D LA TI |
| MD (1) | Meeting Date | D MD |
| ML (1) | Meeting Location | D ML |
| MT (1) | Meeting Title | D MT |
| MY (1) | Meeting Year | D MY |
| NC | Number of Contract | D NC |
| NR | Number of Report | D NR |
| NTE | Note | D NTE |
| PA | Patent Assignee | D PA |
| PB (1) | Publisher | D PB |
| PD (1) | Publication Date | D PD |
| PI | Patent Information | D PI |
| PNO (1) | Patent Number, Original | D PNO |
| PRAI | Priority Information | D PRAI |
| RE | Reference | D RE |
| REC (RE.CNT) (1) | Reference Count | D REC |
| ST | Supplementary Term | D ST |
| TI | Title | D TI |
| UP (1) | Update Date | D UP |
| URL (1) | Uniform Resource Locator | D URL |
| WC.T (1) | Word Count, Title | D WC.T |

DISPLAY and PRINT Formats (cont'd)

| Format | Content | Examples |
|--|---|--|
| ABS ALL DALL IALL BIB IBIB IND MAX TRIAL (TRI, SAMPLE, SAM, FREE) | AN, DN, AB BIB, AB, CC, CCO, CT, CTO, ST, IPC, AO, CHI ALL, delimited for post-processing ALL, indented with text labels AN, DN, TI, AU, CS, NC, NR, SO, AV, DT, CY, LA, Patents: AN, DN, TI, IN, PA, PI, AI, PRAI, DT, CY, LA (BIB is default) BIB, indented with text labels AN, DN, CC, CCO, CT, CTO, ST, IPC, AO, CHI ALL + RE TI, CC, CCO, CT, CTO, ST, IPC, AO, CHI | D ABS D 1-3 ALL D DALL D IALL D BIB D IBIB D IND D MAX D TRI |
| HIT KWIC OCC | Hit term(s) and field(s) Up to 50 words before and after hit term(s) KeyWord-In-Context Number of occurrences of hit term(s) and field(s) in which they occur | D HIT D KWIC D OCC |

(1) Custom display only.

(2) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

| Field Name | Field Code | ANALYZE/ SELECT (1) | SORT |
|---|------------|------------------------|------|
| Abstract | AB | Y | N |
| Accession Number | AN | Y | N |
| Application Date | AD | Y | Y |
| Astronomical Object | AO | Y | Y |
| Author | AU | Y | Y |
| Chemical Indexing | CHI | Y | N |
| Citation | CIT | Y (2,3) | N |
| Classification Code | CC | Y | Y |
| Classification Code, Original | CCO | Y | Y |
| CODEN | CODEN | N | Y |
| Controlled Term | CT | Y | N |
| Controlled Term, Original | CTO | Y | N |
| Corporate Source (patent assignee) | CS (PA) | Y | Y |
| Corporate Source Identifier (Ringgold Identifier (RIN)) | CSID | Y | Y |
| Country of Publication | CY | Y | Y |
| Document Number | DN | Y | Y |
| Document Type | DT (TC) | Y | Y |
| E-mail Address | EML | Y | Y |
| Entry Date | ED | Y | Y |
| International Patent Classification | IPC | Y | N |

SELECT, ANALYZE, and SORT Fields (cont'd)

| Field Name | Field Code | ANALYZE/ SELECT (1) | SORT |
|--|--------------|------------------------|------|
| International Standard (Document) Number | ISN | Y (4) | Y |
| International Standard Book Number | ISBN | N | Y |
| International Standard Serial Number | ISSN | N | Y |
| Journal Title | JT | Y | Y |
| Journal Title, Abbreviated | JTA | Y (5) | Y |
| Journal Title, Full | JTF | Y (5) | Y |
| Language | LA | Y | Y |
| Meeting Date | MD | Y | Y |
| Meeting Location | ML | Y | Y |
| Meeting Title | MT | Y | Y |
| Meeting Year | MY | Y | Y |
| Note | NTE | Y | Y |
| Number of Contract | NC | N | Y |
| Number of Report | NR | Y | Y |
| Occurrence Count of HIT Terms | OCC | N | Y |
| Patent Country | PC | Y | Y |
| Patent Number | PN | Y | Y |
| Patent Number, Original | PNO | Y | Y |
| Priority Information, Original | PRAO | N | Y |
| Priority Year | PRY | Y | Y |
| Publication Date | PD | Y | Y |
| Publication Year | PY | Y | Y |
| Publisher | PB | Y | Y |
| Reference Count | REC (RE.CNT) | Y | Y |
| Source | SO | Y (6) | N |
| Supplementary Term | ST | Y | N |
| Title | TI | Y (default) | Y |
| Uniform Resource Locator | URL | Y | Y |
| Update Date | UP | Y | Y |
| Word Count, Title | WC.T | Y | Y |

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g. SEL HIT TI.
- (2) SELECT HIT and ANALYZE HIT are not valid with this field.
- (3) SELECT HIT or ANALYZE CIT allows you to extract the reference from the source documents in this file and have them automatically converted to a citation format for searching in the SCISEARCH file. SEL or ANALYZE CIT extracts first author, publication year, volume, first page, with a truncation symbol and with /RE appended to the terms created by SELECT.
- (4) Selects or analyzes CODEN, ISSN, and ISBN, and appends /ISN to the terms created by SELECT.
- (5) Appends /JT to the terms created by SELECT.
- (6) Selects or analyzes CODEN, ISSN and ISBN, and appends /SO to the terms created by SELECT.

Sample Records**DISPLAY BIB of JOURNAL**

AN 2021:20413648 INSPEC
 DN 20413648
 TI An "on-off" electrochemiluminescence immunosensor for PIVKA-II detection based on the dual quenching of CeO₂-Au-g-C₃N₄ hybrids by Ag nanocubes-VB2
 AU Zhujun Ai(1); Ke Chen(1); Hua Tang(1); Min Zhao(2); Daobin Han(2); Dongmei Xiong(3)
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 SO Biosensors and Bioelectronics (1 May 2021), Volume 179, pp. 92-99, 41 refs.
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 PUI S0956-5663(21)00096-8
 CY Netherlands
 DT Journal; Practical; Experimental
 FS INSPEC 1969-; A; B
 LA English
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DISPLAY ALL of ARCHIVE

AN 1899A00035 INSPEC
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 TI New radio-active element in pitch blende
 AU Curie, P.; Sklodowska-Curie
 SO Comptes Rendus Hebdomadaires des Seances de l'Academie des Sciences (1898), Volume 127, pp. 175-178
 CY France
 DT Journal
 FS INSPEC 1898-1968; A
 LA English
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 AB The suggestion that pitch blende contains some substance more active than uranium (see Abstract Number 1898A01224) has been followed up and found to be true. It is present in the sulphides precipitated by sulphuretted hydrogen from an acid solution of pitch blende, and is so in company with lead, bismuth, copper, arsenic, and antimony. Sulphide of ammonium removes the arsenic and the antimony, nitric acid dissolves the remaining sulphides, and sulphuric acid removes the lead; the sulphate of lead should be well washed with dilute sulphuric acid in order to recover the portion of the element sought for, which is carried down by the precipitate. There remains in solution the new element, with bismuth and copper: ammonia in excess precipitates the two former. No good method has been found for completely separating these by wet methods, but the two sulphides have different volatilities, and when sublimed in a vacuum tube condense at different parts of the tube. The ultimate product is a sulphide 400 times as active as uranium, and appears to be that of a new metal, analytically related to bismuth: name proposed, Polonium. There is, however, no characteristic ray in its spectrum; but this is the character of the spectra of uranium, thorium, and tantalum, which present merely innumerable very fine lines,

difficult to recognise.
CC A4200 Optics
CCO Light
CT rays
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